

MENU

SEARCH

INDEX

DETAIL

1/1



JAPANESE PATENT OFFICE

## PATENT ABSTRACTS OF JAPAN

(11)Publication number: 11142437

(43)Date of publication of application: 28.05.1999

(51)Int. Cl.

G01R 1/073  
H01L 21/66

(21)Application number: 09303972

(71)Applicant:

MITSUBISHI ELECTRIC CORP

(22)Date of filing: 06.11.1997

(72)Inventor:

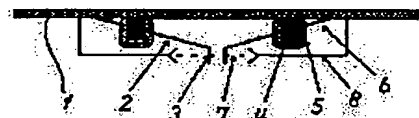
MIZUTA MASAHARU

## (54) PROBE CARD AND MANUFACTURE THEREOF

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a high-precision and low-cost probe card for a semiconductor testing device, which sufficiently copes with an increased number of the same sides in a wafer test of increasingly fine-pitched ICs.

SOLUTION: The probe card, which has probe needles 2 adapted to be put into contact with electrodes on a semiconductor wafer chip for an electrical test, is provided with a guide plate 7 that has a guide hole through which the tips 3 of the probes 2 pass so that the guide hole guides the tips 3 of the probes 2 while the probes 2 are overdriven for electrode contact.



## LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]

Copyright (C); 1998 Japanese Patent Office